
**Nanotechnologies — Requirements
and recommendations for the
identification of measurands that
characterise nano-objects and
materials that contain them**

*Nanotechnologies – Exigences et recommandations pour
l'identification des mesurandes qui caractérisent les nano-objets et les
matériaux les contenant*

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This document was prepared by Technical Committee ISO/TC 229, *Nanotechnologies*, and IEC/TC 113, *Nanotechnology for electrotechnical products and systems*.

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